



Digital Systems Design Automation

Unit 1: Course Introduction and Overview

Lecture 1.6: A Quick Tour of Logic Level Design Automation

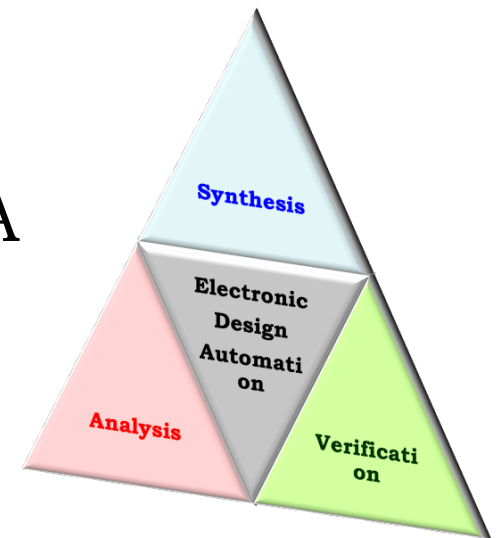


Anand Raghunathan

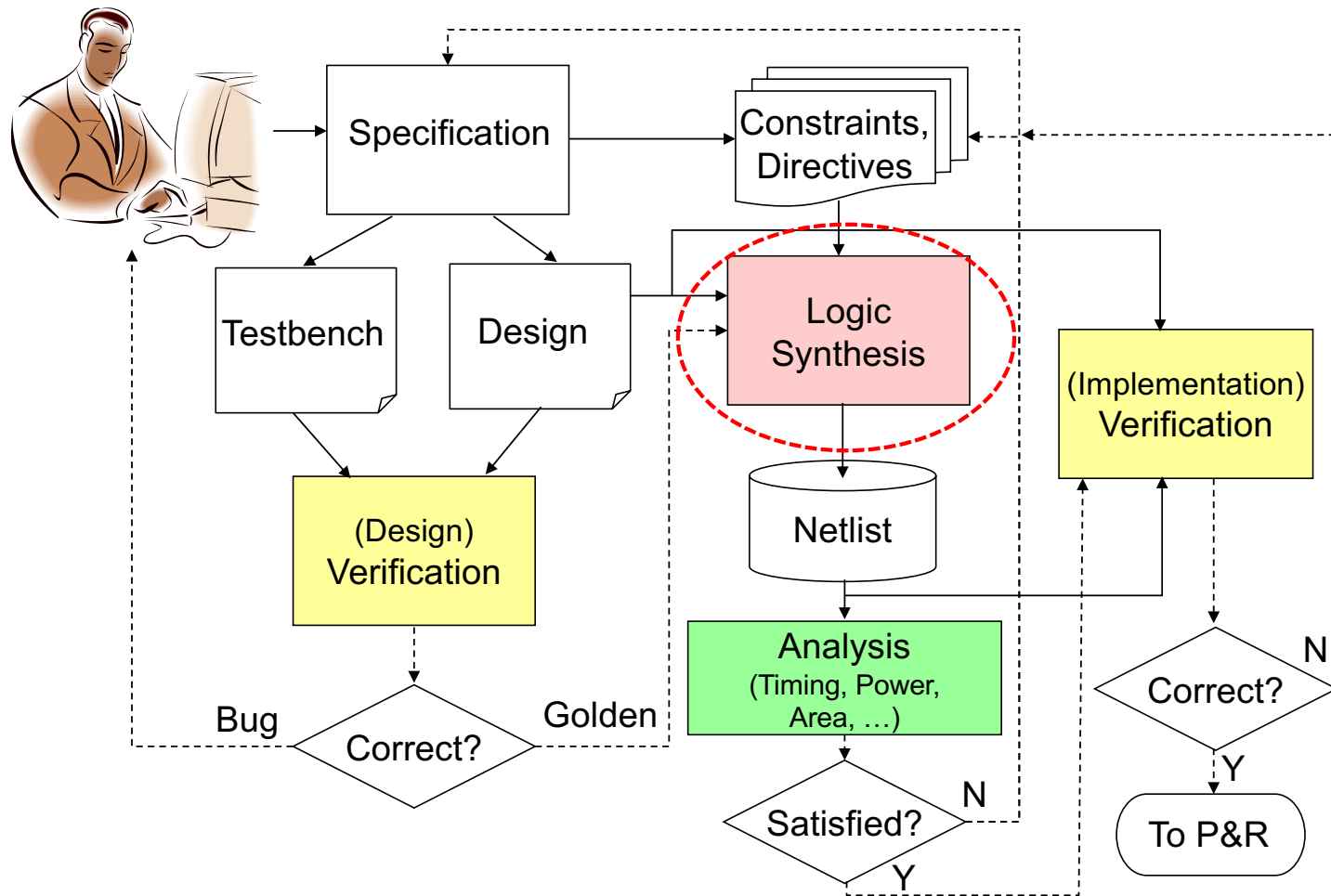
raghunathan@purdue.edu

Outline

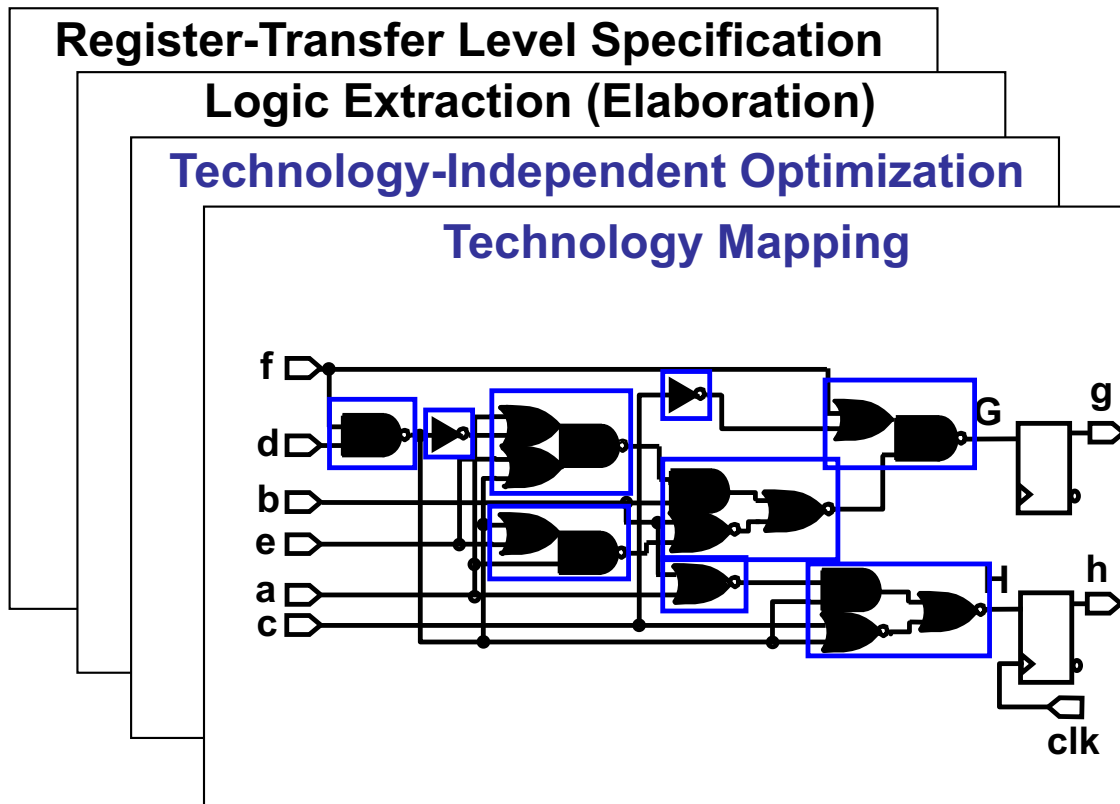
- 1.1 Moore's Law
- 1.2 Design Complexity and need for EDA
- 1.3 Course Overview
- 1.4 Taxonomy of integrated circuits
- 1.5 Levels of abstraction in IC design
- 1.6 A quick tour of logic level design automation



A Closer Look at the Logic Design Flow



Logic Synthesis



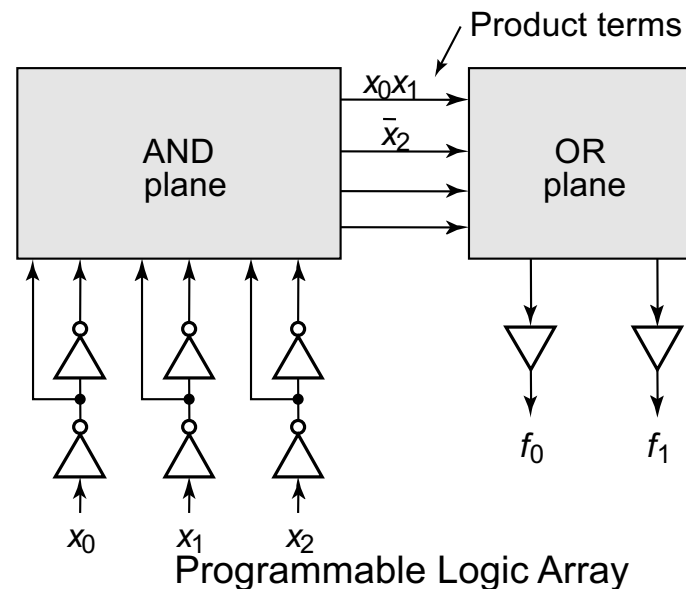
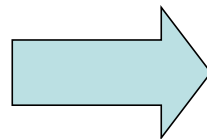
A Quick Tour Through Logic-Level Design Automation

- **Two-level combinational circuit synthesis**
- **Input:** Set of Boolean equations
- **Output:** Minimal two-level implementation
- Used for Programmable Logic Array (PLA) implementations
- Two-level implementations are not very scalable, but synthesis techniques are useful in multi-level context as well

$$f_0 = x_0x_1 + \bar{x}_2$$

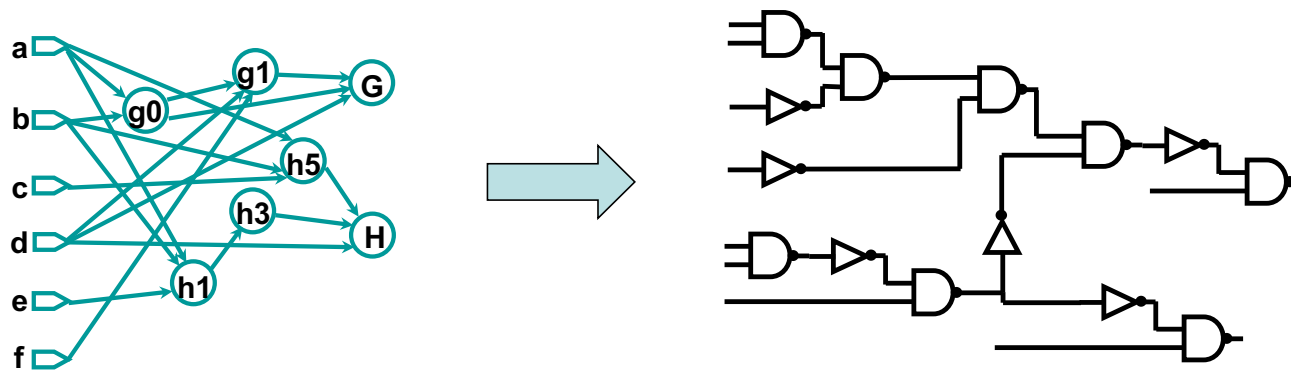
$$f_1 = x_0x_1x_2 + \bar{x}_2 + \bar{x}_0x_1$$

Any combinational logic function can be expressed in the form of Boolean equations



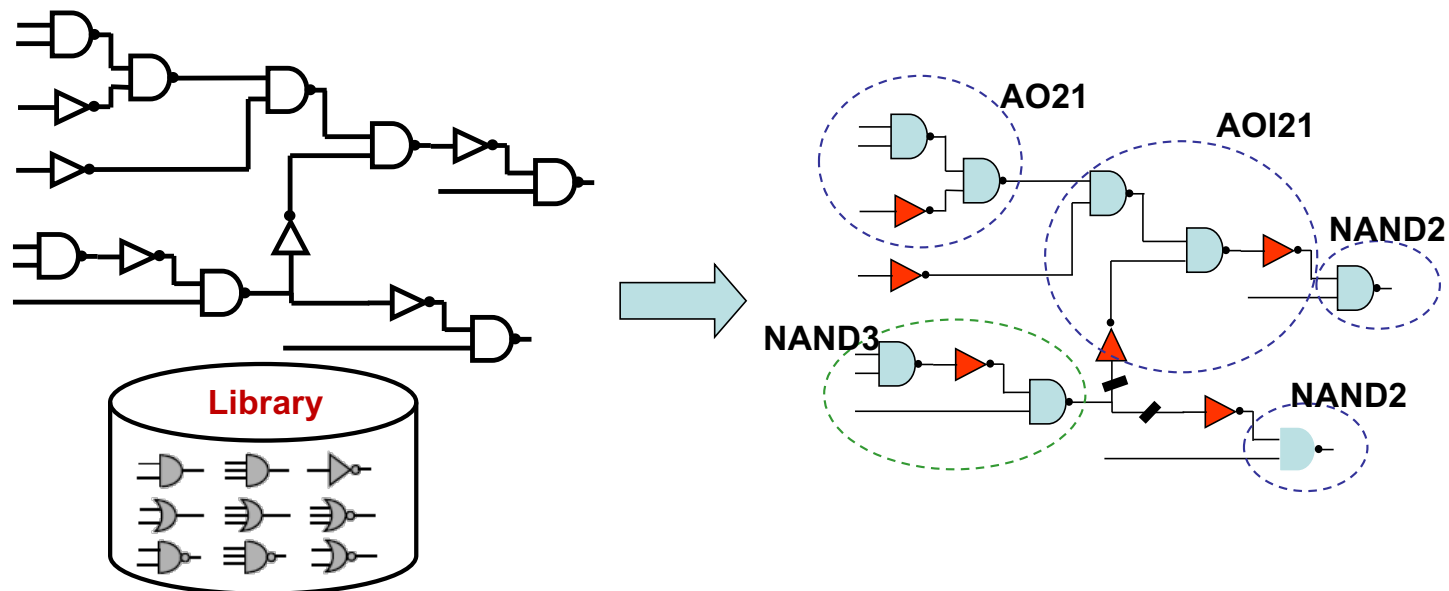
A Quick Tour Through Logic-Level Design Automation

- **Multi-level combinational circuit synthesis**
- **Input:** Set of Boolean equations OR un-optimized Boolean network elaborated from HDL
- **Output:** Optimized multi-level implementation (network of gates)



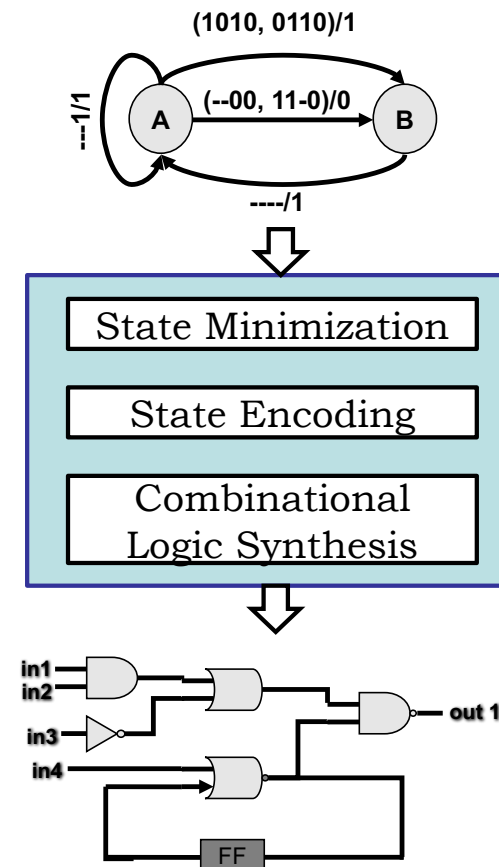
A Quick Tour Through Logic-Level Design Automation

- **Technology Mapping**
- **Input:** Technology-independent implementation, Cell library
- **Output:** Implementation mapped to cells in library



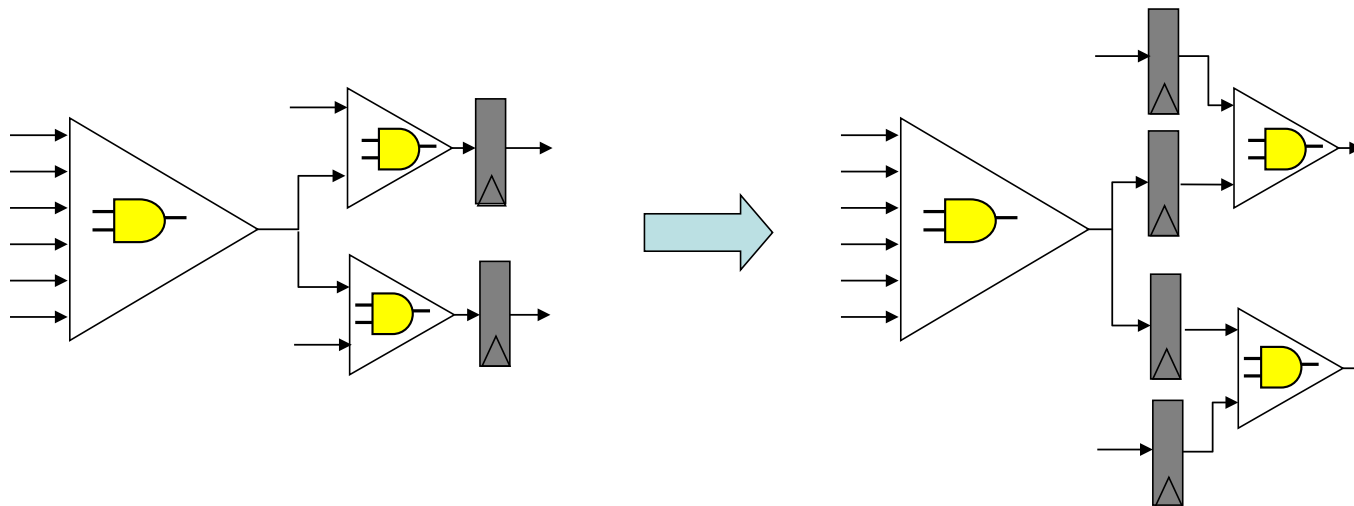
A Quick Tour Through Logic-Level Design Automation

- **Sequential Logic Optimization: FSM Synthesis**
- **Input:** Finite State Machine specification
- **Output:** Optimized implementation (circuit consisting of logic gates and storage elements)

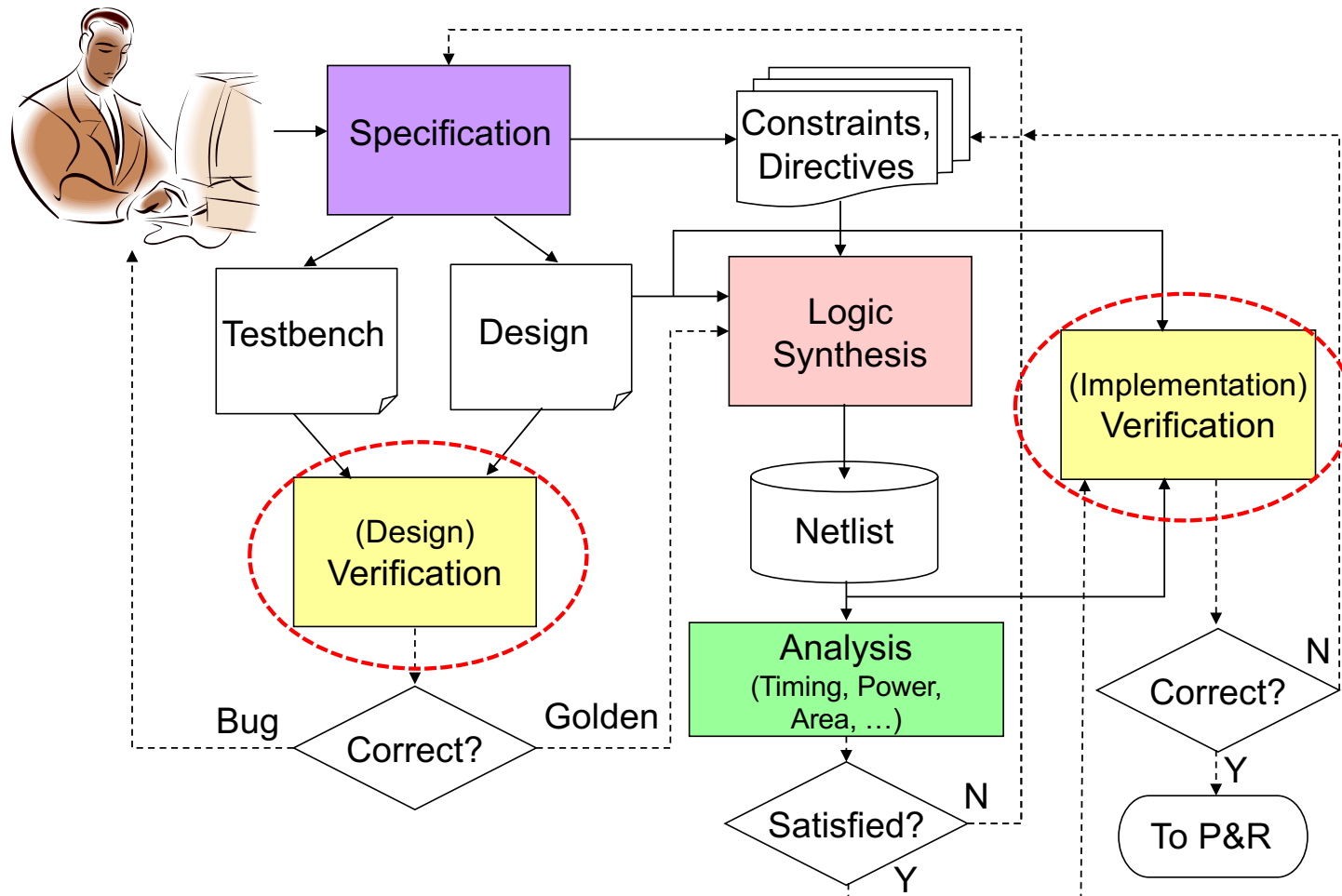


A Quick Tour Through Logic-Level Design Automation

- **Sequential Logic Optimization: Retiming**
- **Input:** Structural implementation consisting of gates and FFs
- **Output:** Optimized implementation with improved area / speed / power.

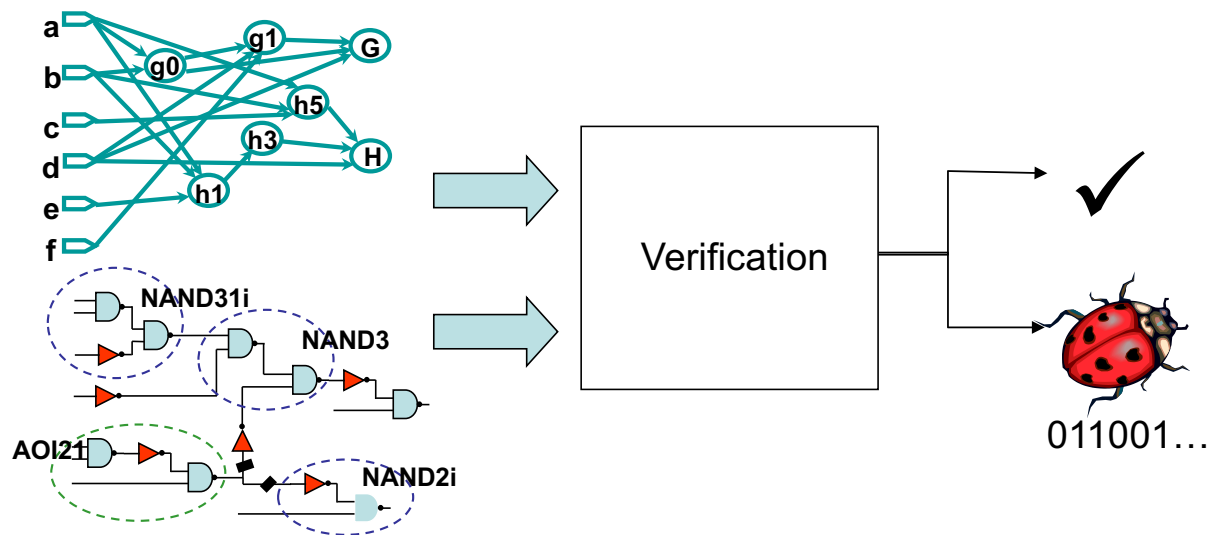


A Closer Look at the Logic Design Flow



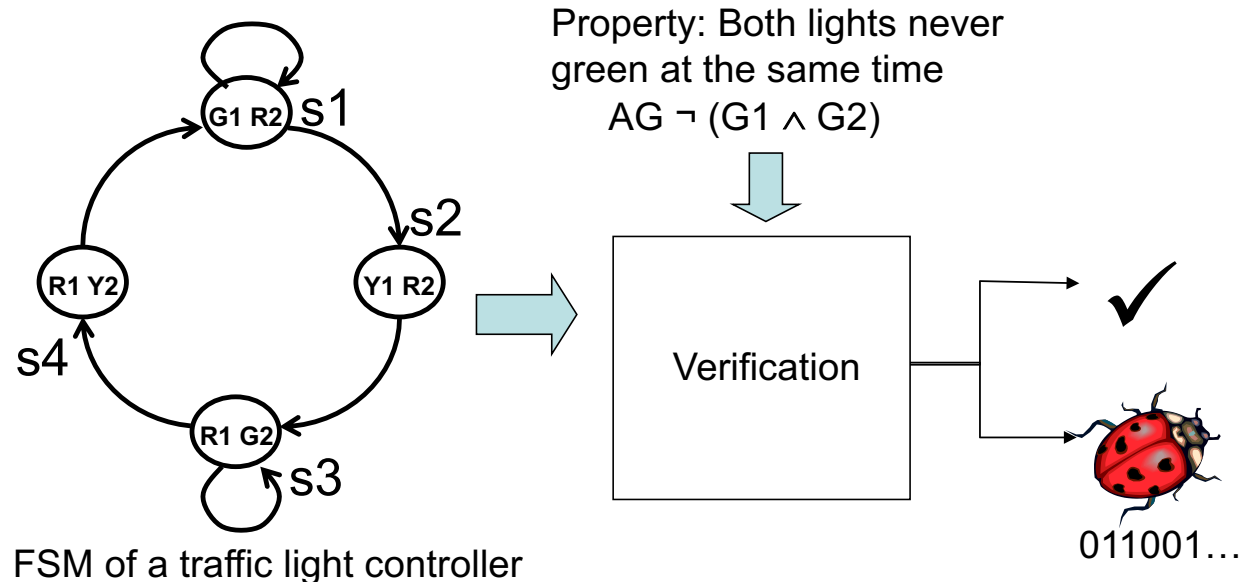
A Quick Tour Through Logic-Level Design Automation

- **Verification: Equivalence Checking**
- **Input:** Specification (RTL, Boolean equations), Optimized implementation (netlist)
- **Output:** Proof that specification == implementation OR counterexample demonstrating otherwise



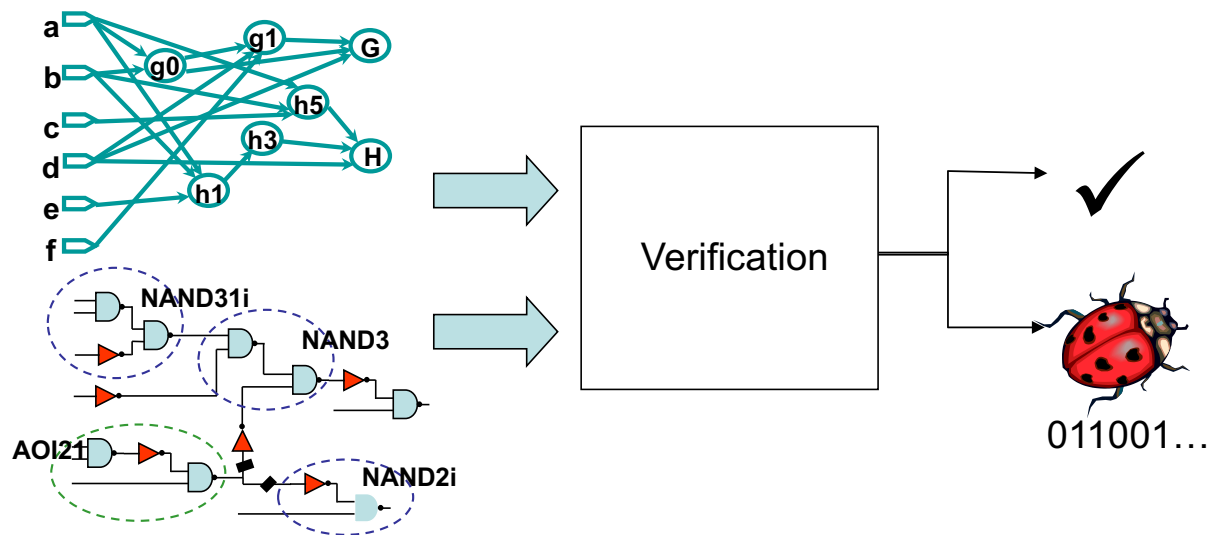
A Quick Tour Through Logic-Level Design Automation

- **Verification: Property Checking**
- **Input:** Specification or implementation, properties that must hold (*e.g.*, assertions)
- **Output:** Proof that property holds OR counterexample demonstrating otherwise



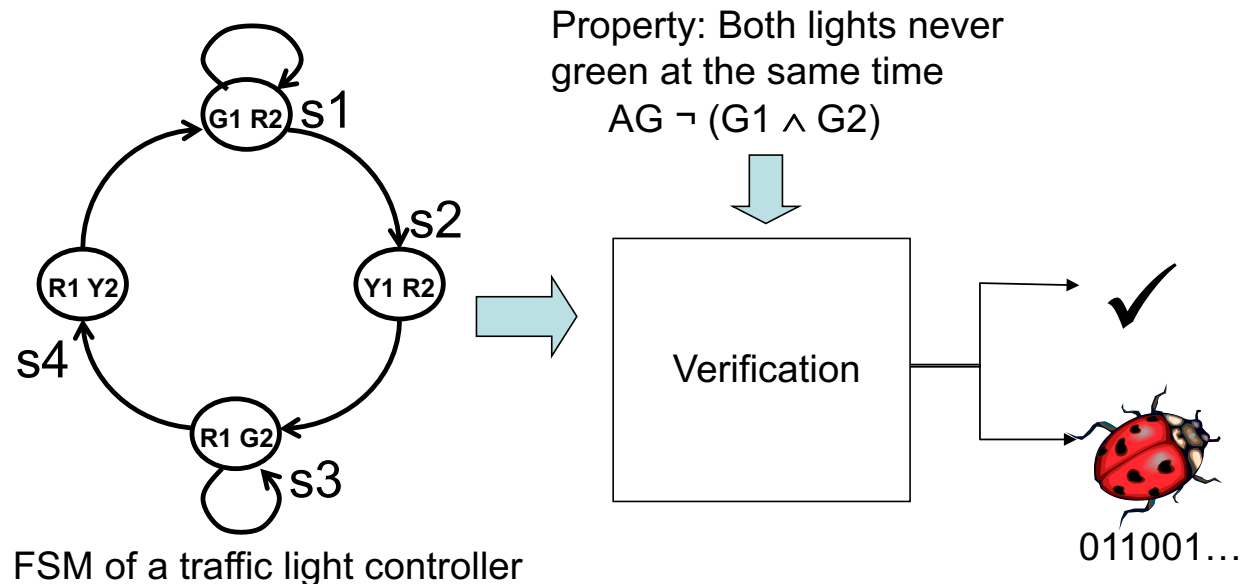
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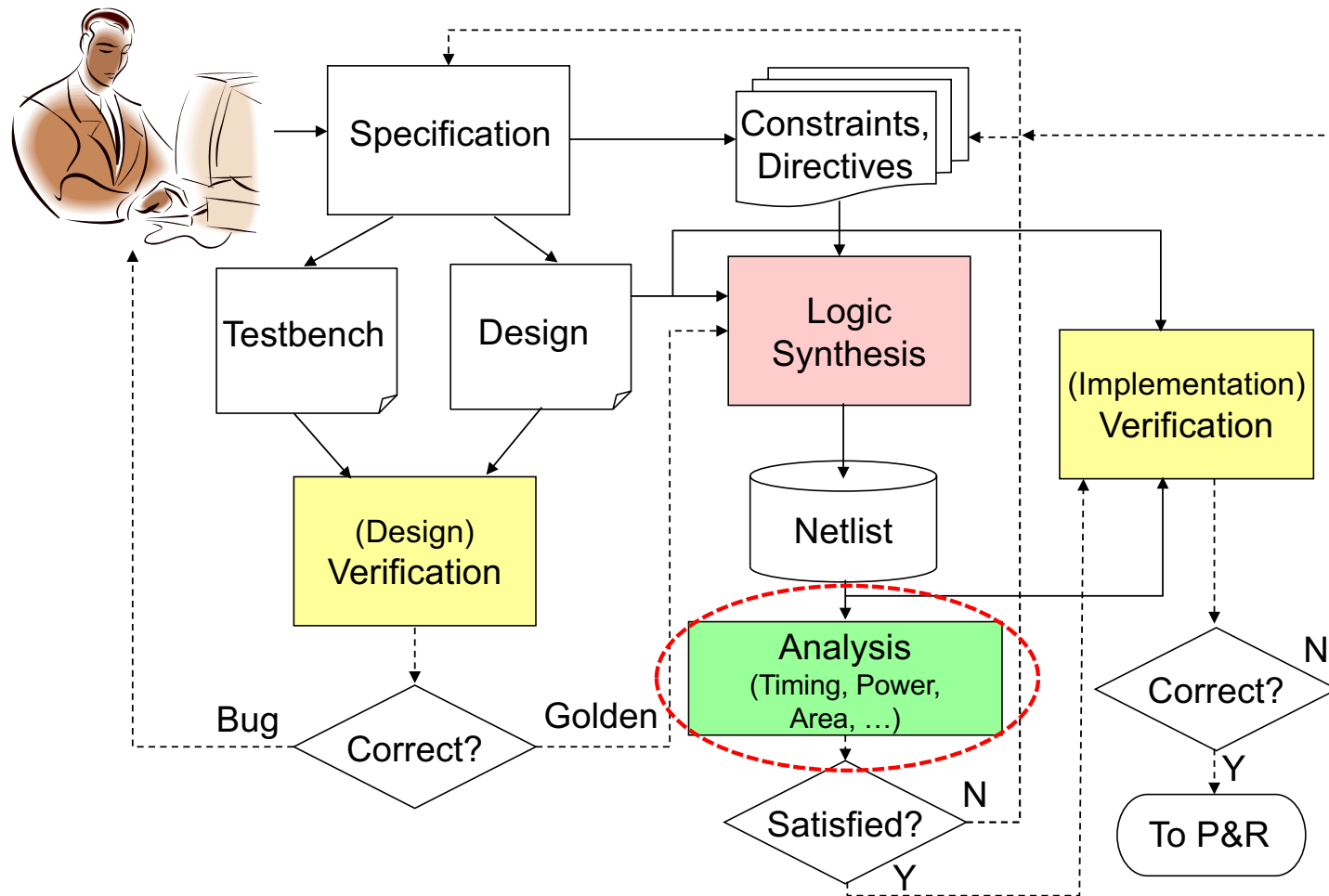


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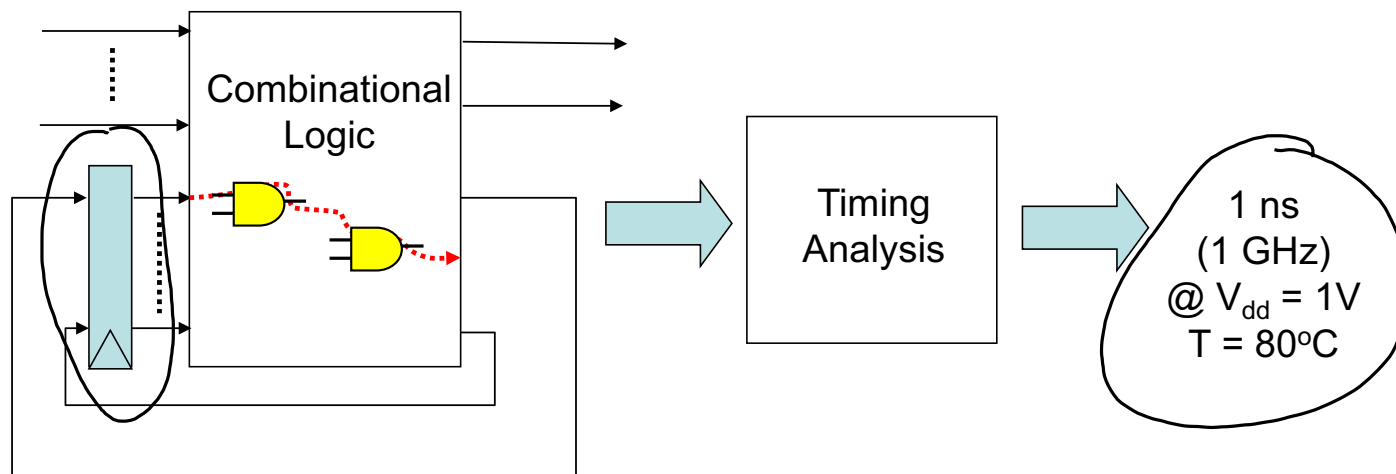


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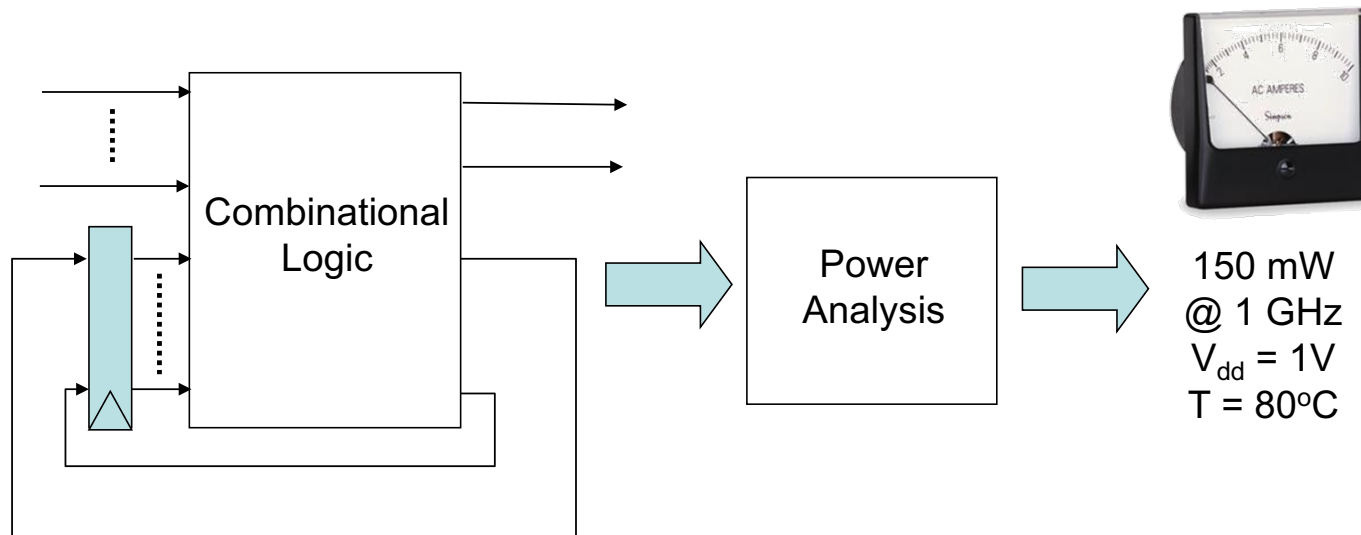
A Quick Tour Through Logic-Level Design Automation

- **Timing Analysis**
- **Input:** Gate-level implementation of a circuit
- **Output:** What is the highest clock frequency (lowest clock period) at which the circuit can operate?
- Simple approach: Find longest combinational path in circuit
- Better (more accurate): Disregard *false paths*



A Quick Tour Through Logic-Level Design Automation

- **Power Analysis**
- **Input:** Gate-level implementation of a circuit
- **Output:** What is the power consumption?
- Different variants: Average vs. peak power, input vectors (workload) given vs. statistical characteristics, dynamic vs. static



Other Topics in EDA

- Manufacturing test (Automatic test pattern generation, Design-for-testability)
- Coupling logic synthesis and physical design
- Analysis & reduction of noise (signal integrity)
- Addressing manufacturing variations (*e.g.*, Statistical timing analysis)
- Bridging the gap between semi-custom and custom design (*e.g.*, custom cell libraries)

Reading for Unit 1

- Review Boolean algebra (your favorite book)
 - Digital Design: Principles & Practices, 4th Ed., John F. Wakerly, Prentice Hall, 2005
 - Purdue ECE270 course material
 - *Module 2: Boolean Algebra and Combinational Logic Circuits*
- De Micheli – Ch 1 (Introduction)
OR
- Hachtel & Somenzi – Ch. 1 (Introduction)